



1/25/2008

**RELIABILITY MONITOR REPORT
FOR**

SVL 1.2 μ m Silicon Gate CMOS

MAXIM Integrated Products

**120 San Gabriel Dr.
Sunnyvale, CA 94086**

**This Report was prepared by
Maxim Reliability Engineering**

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

LM4040AEM3-5.	MAX1644EAE+	MAX1845EEI	MAX5632AETK	MAX6166AESA+
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The calculated failure rate for devices using this process is:

FAILURE RATE: **MTTF (YRS): 105999** **FITS: 1.1**

The parameters used to calculate this failure rate are as follows:

Cf: 60% **Ea: 0.7** **Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between and .

Process Information:

Process Description: SVL 1.2µm Silicon Gate CMOS

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	FA NO
HIGH TEMP OP LIFE	060	MAX5632AETK+	135C, 5.25V	1000 HRS	45	0	
HIGH TEMP OP LIFE	0512	LM4040AEM3-5.0	135C, 5.25V	1000 HRS	76	0	
HIGH TEMP OP LIFE	0545	MAX1845EEI	135C, 5.25V	1000 HRS	77	0	
HIGH TEMP OP LIFE	0601	MAX5632AETK+	135C, 5.25V	1000 HRS	45	0	
HIGH TEMP OP LIFE	0612	MAX6166AESA+	135C, 5.25V	1000 HRS	45	0	
			135C, 5.25V	1000 HRS	45	0	
			135C, 5.25V	1000 HRS	45	0	
			135C, 5.25V	1000 HRS	45	0	
			135C, 5.25V	1000 HRS	45	0	
HIGH TEMP OP LIFE	0619	MAX1644EAE+	135C, 5.25V	1000 HRS	79	0	
				Total:		0	

FAILURE RATE: **MTTF (YRS): 105999** **FITS: 1.1**